PCN# : P682AAB
Issue Date : Sep. 07, 2016

DESIGN/PROCESS CHANGE NOTIFICATION

This is to inform you that a change is being made to the products listed below.

Unless otherwise indicated in the details of this notification, the identified change will have no impact on product quality, reliability, electrical, visual or mechanical performance and affected products will remain fully compliant to all published specifications. Products incorporating this change may be shipped interchangeably with existing unchanged products.

This change is planned to take effect in 90 calendar days from the date of this notification. Please work with your local Fairchild Sales Representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.

Please contact your local Customer Quality Engineer within 30 days of receipt of this notification if you require any additional data or samples.

Implementation of change:

Expected First Shipment Date for Changed Product :Dec. 06, 2016

Expected First Date Code of Changed Product :1650

Description of Change (From) :
CS080CBiH30 Technology product produced at the FSC Bucheon 5”/6” wafer fabrication areas.

Description of Change (To) :
CS080CBiH30 Technology product produced at the FSC Bucheon 5”/6” and S Portland 8” wafer fabrication areas.

Reason for Change:
This change is being made to internally provide second source capability and minimize any risk of disruption of supply.

Affected Product(s):

FAN7930BMX	FAN7930BMX_G	FAN7930CMX
FAN7930CMX_G	FAN7930MX	FAN7930MX_G
FL7930BMX	FL7930BMX_G	FL7930CMX
FL7930CMX_G		

Qualification Plan	Device	Package	Process	No. of Lots
Q20090397	FAN7930MX	SOIC	CS080CBiH30	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precon	MSL1, 260C	JESD22-A113	N/A	0/154
Highly Temperature Operational Life	100% of rated Vcc, 125°C	JESD22A-108	168, 500, 1000hrs	0/77
Temperature Cycling/ TC	-65°C to 150°C, 30 min/cycle	JESD22A-104	500 cycles	0/77
High Temperature Storage Life	150°C	JESD22A-103	1000hrs	0/231
Temperature Humidity Bias Test	85°C, 85%RH, rated Vcc	JESD22A-104	1000hrs	0/231

Qualification Plan	Device	Package	Process	No. of Lots
Q20090073B	FAN5236MTC	SOIC	CS080CBiH30	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precon	MSL1, 260C	JESD22-A113	N/A	0/353
Autoclave	121C, 100%RH	JESD22-A102	96hrs	0/77
Dynamic Operational Life Testing	5.5Vcc, 125°C	JESD22A-108	168, 500, 1000hrs	0/77
Temperature Cycling/ TC	-65°C to 150°C, 30 min/cycle	JESD22A-104	500 cycles	0/77
High Temperature Storage Life	150°C	JESD22A-103	1000hrs	0/77
Highly Accelerated Stress Test	85°C, 85%RH, rated Vcc	JESD22A-110	96hrs	0/45

Title : Qualification Report for PCN : P682AAB

Date : Sep. 06, 2016

Affected devices :

C

Product	Customer Part Number	BBB	Drawing
FL7930BMX		Y	N

C

Product	Customer Part Number	BBB	Drawing
FAN7930BMX		Y	N
FAN7930BMX_G		Y	N
FAN7930CMX_G		Y	N
FL7930BMX_G		Y	N
FL7930CMX_G		Y	N

Qualification Test Summary :

Qualification Plan	Device	Package	Process	No. of Lots
Q20090397	FAN7930MX	SOIC	CS080CBiH30	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precon	MSL1, 260C	JESD22-A113	N/A	0/154
Highly Temperature Operational Life	100% of rated Vcc, 125°C	JESD22A-108	168, 500, 1000hrs	0/77
Temperature Cycling/ TC	-65°C to 150°C, 30 min/cycle	JESD22A-104	500 cycles	0/77
High Temperature Storage Life	150°C	JESD22A-103	1000hrs	0/231
Temperature Humidity Bias Test	85°C, 85%RH, rated Vcc	JESD22A-104	1000hrs	0/231

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Q20090073B	FAN5236MTC	SOIC	CS080CBiH30	1

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MSL1 Precon	MSL1, 260C	JESD22-A113	N/A	0/353
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Dynamic Operational Life Testing	5.5Vcc, 125°C	JESD22A-108	168, 500, 1000hrs	0/77
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High Temperature Storage Life	150°C	JESD22A-103	1000hrs	0/77
Highly Accelerated Stress Test	85°C, 85%RH, rated Vcc	JESD22A-110	96hrs	0/45

The selection methodology of qualification vehicles is aligned with JESD47 and if automotive devices are impacted by the PCN the selection of qualification vehicles is also align with the requirements in AEC-Q100 or AEC-Q101

Please contact your local Customer Quality Engineer if you have any questions concerning this data.